FORM PTO-1449	ATTY. DOCKET NO. I-2-0433.1US	SERIAL NO. 10/698,721	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	APPLICANT Phillip J. Pietraski		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	FILING DATE October 31, 2003	GROUP 2617	
(Use several sheets if necessary)			

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¹ Corresponds to JP 11-313040 and JP11-150571

² Corresponds to JP 2002-084578

EXAMINER	DATE CONSIDERED

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FOREIGN PATENT DOCUMENTS								
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^{**}English Abstract Only

EXAMINER	DATE CONSIDERED